MAXIMUM PERMISSIBLE EXPOSURE FOR EXTENDED SOURCES

Wesley Marshall Laser Safety Specialties

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Maximum Permissible Exposure (MPE)

- Laser exposure limits have been established for
 - Wavelengths between 180 nm to 1 mm
 - Exposure duration between 100 fs and 30,000 s
 - CW, pulsed and repetitively pulsed lasers
 - Point sources and extended sources
- Separate exposure limits
 - Retina, Cornea, Skin
- Due to time constraints, discussion is limited to:
 - Visible wavelengths (400 nm to 700 nm) (e.g. 450 nm)
 - Single retinal exposure > 0.25 s duration (e.g. 10 s)
 - Single location of 10 cm from the emitting source

Damage Mechanisms

- MPEs have been established from empirical data
- Two primary damage mechanisms were observed
 - Thermal damage
 - Irreversible damage due to heating of cells
 - Evidence of injury is immediate
 - MPE is provided as radiant exposure
 - Photochemical damage
 - Damage caused by cell interaction with light that is not dependent on temperature rise in the cells
 - Evidence of injury is often visible 24 hours later
 - MPE is provided as integrated radiance

Retinal Thermal Damage Mechanism

• Point source

- Retinal image of 25 μ m (Angular subtense of 1.5 mrad)
- All power entering the eye contributes to the hazard
- A relaxation of the point source MPE can be applied by the use of a correction factor (C_E) for extended sources
- Intermediate extended source
 - Angular subtense is between 1.5 mrad and 100 mrad
 - $C_{\rm E}$ is equal to the ratio of source angle, α , and 1.5 mrad
- Large extended source
 - Retinal image is larger than 100 mrad
 - Hazard is related to radiance (retinal irradiance)
 - $-C_{\rm E}$ is proportional to the square of the source angle

Retinal Photochemical Damage

Small source

- Retinal image < 187 μ m (11 mrad) for *T* < 100 s
- Definition of "small" increases with exposure duration
- Eye movements blur image so that the averaging cone
 (γ) increases from 11 mrad to 110 mrad at 10,000 s
- All power entering the eye contributes to the hazard regardless of actual size due to normal eye movements
- Large extended source
 - Retinal image is larger than γ (11 mrad for *T*< 100 s), but only the power within γ contributes to the hazard
 - Hazard is related to integrated radiance, which is directly proportional to radiant exposure on the retina

Photochemical MPE

- For all sources, regardless of angular subtense
 - Exposure less than 10,000 s

 $MPE = 100 \times C_B \,\mathrm{J} \cdot \mathrm{cm}^{-2} \cdot \mathrm{sr}^{-1}$

- Exposure greater than 10,000 s

Note that at 10,000 s, the two limits are equal

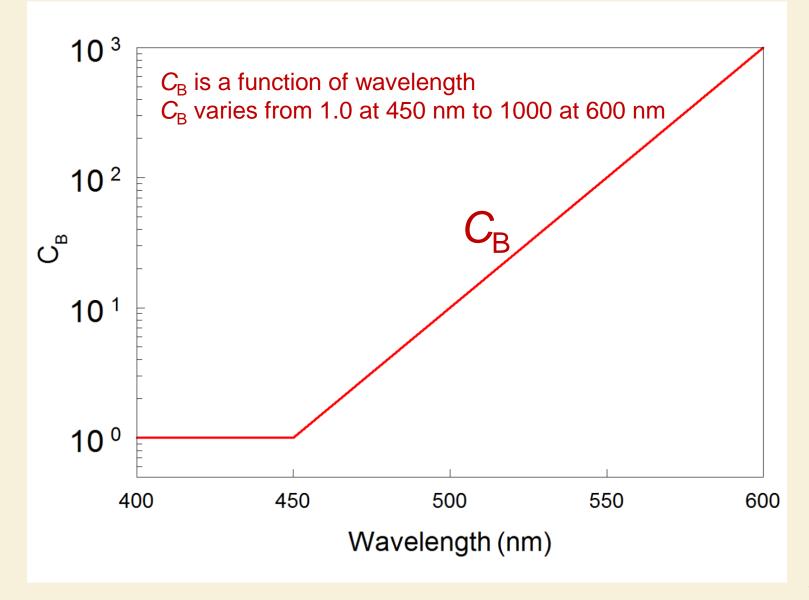
 $MPE = 0.01 \times C_B \,\mathrm{W} \cdot \mathrm{cm}^{-2} \cdot \mathrm{sr}^{-1}$

- Averaged over a cone angle equal to gamma (γ)

 $\gamma = 1.1 \times \sqrt{t} \text{ mrad for } 100 \text{ s} < t < 10,000 \text{ s}$

 Direct comparison between the thermal MPE and the photochemical MPE is hindered because of different units

Photochemical Correction Factor, C_B



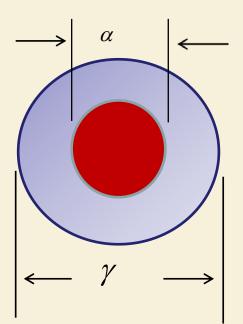
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Small Photochemical Sources

- When $\alpha < \gamma$, the source is a small source
- The solid angle for a small source is averaged over the cone angle γ

$$\Omega_{small} = \frac{\pi \gamma^2}{4}$$

The actual source angle is not used



Photochemical MPE (small source)

- The linear angle of γ is 11 mrad for T < 100 s
- All the power that enters the eye contributes to the hazard for α < γ
- The solid angle of γ is,

$$\Omega_{small} = \frac{\pi \gamma^2}{4} = \frac{\pi \times (0.011)^2}{4} = 9.5 \times 10^{-5} \text{ sr}$$

• This solid angle is rounded to 1×10^{-4} sr (5% error)

Photochemical MPE as Radiant Exposure

- For small sources ($\alpha \leq \gamma$) and T < 100 s
- The MPE as radiant exposure is computed by multiplying $MPE:L_P$ by Ω_{small} $MPE:H_{ph} = MPE:L_p \times \Omega_{small}$ $MPE:H_{ph} = (100 \times C_B \text{ J} \cdot \text{cm}^{-2} \cdot \text{sr}^{-1}) \times (1 \times 10^{-4} \text{ sr})$
- The photochemical MPE for small sources is then: $MPE: H_{\text{ph small}} = 0.01 \times C_B \text{ J} \cdot \text{cm}^{-2}$
- For small sources, the photochemical MPE can be compared directly with the thermal MPE

Example 1: MPE (small source)

- Diode laser, 5 mW power at 450 nm ($C_{\rm B} = 1$) 3 mm beam, 3 mrad source at 10 cm from exit
- Calculate MPE for 10 s exposure
- Photochemical
 - Small source since 3 mrad < 11 mrad</p>

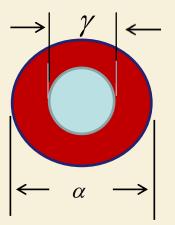
$$MPE: H = 0.01 \text{ J} \cdot \text{cm}^{-2} \qquad MPE: E = \frac{MPE: H}{T}$$

- MPE = $1.0 \text{ mW} \cdot \text{cm}^{-2}$ (same MPE as thermal point source)

- Thermal
 - Intermediate source since 3 mrad is twice 1.5 mrad
 - $-C_{\rm E} = 2$ and MPE = 2.0 mW·cm⁻²

Large Photochemical Source

• For a large source ($\alpha > \gamma$), the hazard is based on the angular subtense of the source, α



 Averaging over γ is not necessary for larger sources and γ is not used in the evaluation

$$\Omega_{source} = \frac{\pi \, \alpha^2}{4}$$

Photochemical MPE (large source)

• The same photochemical MPE applies to all sources

$$MPE: L_p = 100 \times C_B \,\mathrm{J} \cdot \mathrm{cm}^{-2} \cdot \mathrm{sr}^{-1}$$

 However, for large sources, the solid angle of the source is used to compute the MPE

 $MPE: H_{\text{ph(large)}} = MPE: L_p \times \Omega_{\text{source}}$

Example 2: Photochemical MPE (large source)

- Diffuse reflection, 5 mW power at 450 nm, 3 mm beam, 30 mrad source at 10 cm from target
- Calculate MPE for 10 s exposure ($C_B = 1$)
- Since 30 mrad > 11 mrad $\Omega_{source} = \frac{\pi \alpha^2}{4} = \frac{\pi \times (0.03)^2}{4} = 7.07 \times 10^{-4} \text{ sr}$ $MPE : H = 100 \text{ J} \cdot \text{cm}^{-2} \cdot \text{sr}^{-1} \times 7.07 \times 10^{-4} \text{ sr}$
- MPE = 70.7 mJ⋅cm⁻²
- MPE = 7.07 mW·cm⁻² for 10 s

Correction Factor Method

- Proposal is to use a correction factor (C_{blue}) to adjust the small source MPE for large sources
- The ratio between the small source MPE and the large source MPE may be computed

 $ratio = \frac{MPE : H_{ph(large)}}{MPE : H_{ph(small)}} = \frac{MPE : L_p \times \Omega_{source}}{MPE : L_p \times \Omega_{small}}$ $ratio = \frac{MPE : L_p \times (\pi \alpha^2 / 4)}{MPE : L_p \times (\pi \gamma^2 / 4)} = \frac{\alpha^2}{\gamma^2}$ $C_{blue} = \frac{\alpha^2}{\gamma^2} \quad \text{for } \alpha > \gamma$

This factor is in footnote 3 of Table 5e of ANSI Z136.1(2014)

Example 2 Using Correction Factors

- Diffuse reflection, 5 mW power at 450 nm, 3 mm beam, 30 mrad source at 10 cm from target
- MPE = $1.0 \text{ mW} \cdot \text{cm}^{-2}$ for 10 s for small/point source

$$C_{blue} = \frac{\alpha^2}{\gamma^2} = \frac{(30 \text{ mrad})^2}{(11 \text{ mrad})^2} = 7.44$$

The thermal and photochemical point source MPEs are the same for 10 s

- $MPE = 7.44 \text{ mW} \cdot \text{cm}^{-2} \text{ for } 10 \text{ s}$
- This MPE is 5% greater than computed earlier
- Thermal
 - Intermediate source since 30 mrad < 100 mrad
 - $C_{\rm E} = 30/1.5 = 20$
 - $MPE = 20 \text{ mW} \cdot \text{cm}^{-2} \text{ for } 10 \text{ s}$

Thoughts on Using C_{blue}

- For large retinal images, the hazard is related to the retinal irradiance
- Only the portion inside γ contributes to the hazard
- The factor α²/γ² effectively eliminates power outside of γ by increasing the MPE
- An alternate approach would be to eliminate the portion outside of y from the power measurement by restricting the field of view of the instrument
- This alternate method is used in IEC 60825-1

Elongated Extended Sources

- Elongated sources present unique challenge
- Source consists of α_x and α_y
- The larger source angle is defined by α_x
- Includes both rectangular and elliptical sources
 - For thermal evaluation, a correction to the point source MPE may be used
 - For photochemical evaluation, the evaluation has been based on radiance using an averaging cone of γ
- By effectively eliminating the power outside of γ, a correction factor method is still possible

Photochemical MPE (narrow elongated source)

• The portion outside of γ does not contribute to the hazard $\rightarrow \gamma \mid \leftarrow \quad Make \alpha_x$ the larger dimension

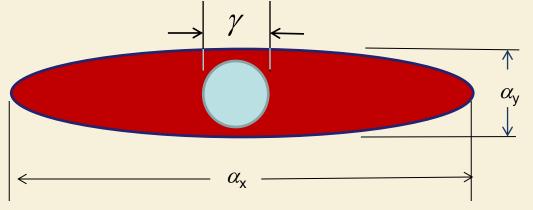
 $\alpha_{\rm v}$

- The fraction of energy inside the cone is γ / α_x
- Increase the MPE by α_x/γ for source larger than γ

$$MPE: E_{\text{large}} = \left(\frac{\alpha_x}{\gamma}\right) \times MPE: E_{\text{small}}$$
$$MPE: E_{\text{large}} = \left(\frac{\alpha_x}{\gamma}\right) \times 1 \times 10^{-4} C_B \text{ W} \cdot \text{cm}^{-2}$$

Photochemical MPE (larger rectangular source)

- Both dimensions larger than γ
- Only the portion inside γ contributes to the hazard



• The fraction inside the cone is $(\gamma/\alpha_x) \times (\gamma/\alpha_v)$

$$MPE: E_{\text{large}} = \left(\frac{\alpha_x \times \alpha_y}{\gamma^2}\right) \times 1 \times 10^{-4} \ C_B \text{W} \cdot \text{cm}^{-2}$$

Conclusion

- Having the thermal MPE and Photochemical MPE in the same units allows easier hazard comparison
- Extended source photochemical correction factors may appear next to those for thermal in the next edition of ANSI Z136.1

$$C_{blue} = 1.0 \text{ for } \alpha < \gamma \qquad C_{blue} = \frac{\alpha}{\gamma^2} \text{ for } \alpha > \gamma$$

• For a rectangular or elliptical source

$$C_{blue} = \frac{\alpha_x}{\gamma} \quad \text{for } \alpha_x > \gamma \text{ and } \alpha_y < \gamma$$
$$C_{blue} = \frac{\alpha_x \times \alpha_y}{\gamma^2} \quad \text{for } \alpha_x > \gamma \text{ and } \alpha_y > \gamma$$